

## 12500 TI Boulevard, MS 8640, Dallas, Texas 75243

# PCN# 20180925002.1 Qualification of TI Malaysia as an additional Assembly Site for select devices Change Notification / Sample Request

**Date:** October 05, 2018

To: TOKYO ELECTRON DEVICE (DSTR) PCN

### Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The proposed first ship date is indicated on page 3 of this notification, unless customer agreement has been reached on an earlier implementation of the change.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN www admin team@list.ti.com).

Sincerely, PCN Team SC Business Services

PCN Number:			20	20180925002.1 <b>PCN Date:</b> Oct. 5, 2					Oct. 5, 2018				
			of TI Malaysia as an additional Assembly Si				<u> </u>	,					
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<b>Customer Contact:</b>		PCN	PCN Manager			pt:	Quality Serv						
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Desc	cription	on of Change	<b>e:</b>										
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		Differences: Device:											
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Reas	Reason for Change:												
	Continuity of supply.												
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):													
None													
		ed impact or	ı Ma	terial C	)ecl	arat	ion						
No Impact to the Material Declaration		on	M p r o n	Material Declarations or Product Content reports are driven from production data and will be available following the production release. Upon production release the revised reports can be obtained from the <a href="II Eco-Info website">II Eco-Info website</a> . There is no impact to the material meeting current regulatory compliance requirements with this PCN change.				ne production ports can be no impact to the					
		to product ic		£: L: _		14	: E		L'- DCN				

Assembly Site						
Microchip Technology	Assembly Site Origin (22L)	ASO: ALP				
TI Malaysia	Assembly Site Origin (22L)	ASO: MLA				

Sample product shipping label (not actual product label)





(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483\$I2 (P) (2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASP: MLA (23L) ACO: MYS

## **Group 1 Product Affected:**

UC2875N	UC3875N	UC3876N
00207311	00307311	00307011

## **Group 2 Product Affected:**

UC2638N	UC3638N	UC3879N	UCC38502N
UC2855BN	UC3638NG4	UCC28500N	UCC38502NG4
UC2875NG4	UC3855BN	UCC2895N	UCC3895N
UC2879N	UC3855BNG4	UCC38500N	UCC3895NG4
UC2879NG4	UC3875NG4	UCC38501N	

# **Qualification Report**

## MMT Offload Qualification for PDIP 20N devices

Approve Date 25-May-2018

## **Product Attributes**

Attributes	Qual Device: <u>UC3875N</u>	Qual Device: <u>UCC38501N</u>	QBS Package Reference: <u>SN74HCT540N</u>	QBS Package Reference: <u>TPA3122D2N</u>	
Assembly Site	MLA	MLA	MLA	MLA	
Package Family	PDIP	PDIP	PDIP	PDIP	
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	
Wafer Fab Supplier	SFAB	SFAB	SFAB	UMC FAB8AB	
Wafer Fab Process	JI_PWR2	IMP-PWR2	74HC-NONEPI	LBC5X	

<sup>-</sup> QBS: Qual By Similarity

## **Qualification Results**

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: <u>UC3875N</u>	Qual Device: <u>UCC38501N</u>	QBS Package Reference: SN74HCT540N	QBS Package Reference: <u>TPA3122D2N</u>
AC	Autoclave 121C	96 Hours	3/231/0	3/231/0	3/231/0	3/231/0
FLAM	Flammability (UL 94V-0)	-	-	-	3/15/0	-

<sup>-</sup> Qual Devices UC3875N and UCC38501N are qualified at Not Classified

Туре	Test Name / Condition	Duration	Qual Device: <u>UC3875N</u>	Qual Device: <u>UCC38501N</u>	QBS Package Reference: <u>SN74HCT540N</u>	QBS Package Reference: <u>TPA3122D2N</u>
HTSL	High Temp Storage Bake 170C	420 Hours	3/231/0	3/231/0	3/231/0	3/231/0
LI	Lead Fatigue	Leads	-	-	3/45/0	3/45/0
LI	Lead Pull to Destruction	Leads	-	-	3/180/0	3/180/0
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	Pass	Pass	Pass	Pass
PKG	Lead Finish Adhesion	Leads	-	-	2/30/0	3/45/0
SD	Solderability	8 Hours Steam Age	3/30/0	3/30/0	3/66/0	3/66/0
TC	Temperature Cycle, - 65/150C	500 Cycles	3/231/0	3/231/0	3/231/0	3/231/0

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

#### Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

THIS INFORMATION RELATING TO QUALITY AND RELIABILITY IS PROVIDED "AS IS." Product information detailed in this report may not accurately reflect Tl's current product materials, processes and testing used in the construction of the TI products. Customers are solely responsible to conduct sufficient engineering and additional qualification testing to determine whether a device is suitable for use in their applications. Using TI products outside limits stated in Tl's datasheet may void Tl's warranty. See Tl's Terms of Sale at "http://www.ti.com/lsds/ti/legal/termsofsale.page"

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com